

FCC ID: QTG-BAQNALT

Portable device

According to §15.247(e)(i) and §1.1307(b)(1), systems operating under the provisions of this section shall be operated in a manner that ensures that the public is not exposed to radio frequency energy level in excess of the Commission’s guidelines.

According to KDB447498 D01 General RF Exposure Guidance V06

The 1-g SAR and 10-g SAR test exclusion thresholds for 100 MHz to 6 GHz at test separation distances ≤ 50 mm are determined by:

$[(\text{max. power of channel, including tune-up tolerance, mW}) / (\text{min. test separation distance, mm})] \cdot \sqrt{f(\text{GHz})} \leq 3.0$ for 1-g SAR and ≤ 7.5 for 10-g extremity SAR, where:

- f(GHz) is the RF channel transmit frequency in GHz
- Power and distance are rounded to the nearest mW and mm before calculation
- The result is rounded to one decimal place for comparison

When the minimum test separation distance is < 5 mm, a distance of 5 mm is applied to determine SAR test exclusion.

BT:

Modulation	Channel Freq. (GHz)	Conduct ed power (dBm)	Conducte d power (mW)	Tune-up power (dBm)	Max tune-up power (dBm)	Max tune-up power (mW)	Distance (mm)	Result calculatio n	SAR Exclusion threshold	SAR test exclusion
GFSK (BLE)	2.402	-2.92	0.51	-2±1	-1	0.79	<5	0.24622	3.00	YES
	2.44	-1.76	0.67	-1±1	0	1.00	<5	0.31241	3.00	YES
	2.480	-2.06	0.62	-2±1	-1	0.79	<5	0.25018	3.00	YES
GFSK	2.402	7.189	5.23	8±1	9	7.94	<5	2.46216	3.00	YES
	2.44	8.355	6.85	8±1	9	7.94	<5	2.48156	3.00	YES
	2.480	8.278	6.73	8±1	9	7.94	<5	2.50182	3.00	YES
π/4-DQPSK	2.402	7.562	5.70	7.5±1	8.5	7.08	<5	2.19440	3.00	YES
	2.44	6.899	4.90	7.5±1	8.5	7.08	<5	2.21169	3.00	YES
	2.480	8.441	6.98	7.5±1	8.5	7.08	<5	2.22975	3.00	YES
8-DPSK	2.402	6.741	4.72	7.5±1	8.5	7.08	<5	2.19440	3.00	YES
	2.44	8.103	6.46	7.5±1	8.5	7.08	<5	2.21169	3.00	YES
	2.480	7.865	6.12	7.5±1	8.5	7.08	<5	2.22975	3.00	YES

Conclusion:

For the max result : 2.50182W/Kg ≤ 3.0 for 1g SAR, No SAR is required.

Signature:

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